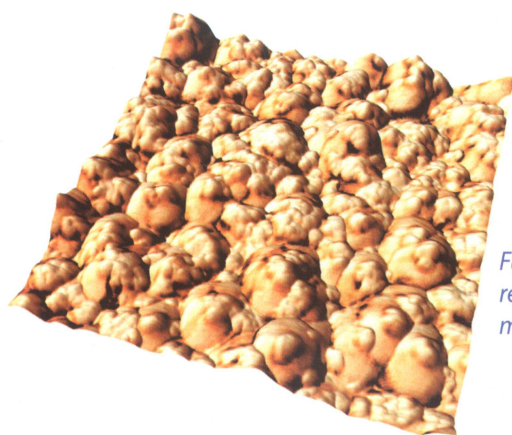
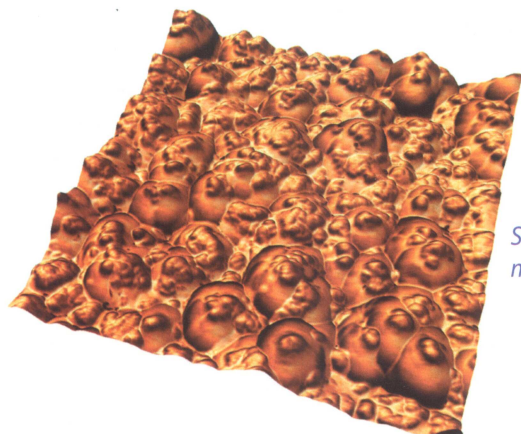




Fundamental
resonance
mode phase



Second resonance
mode amplitude

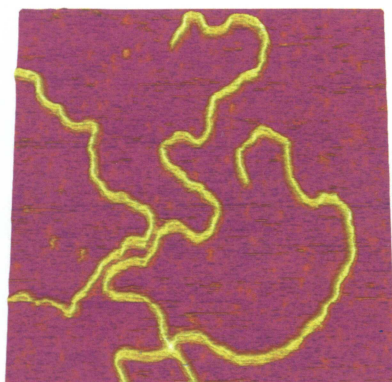
Figure 5: ZnO. Fundamental resonance mode phase data overlaid on the rendered topography (top) and second resonance mode amplitude (Dual AC Mode) data overlaid on the topography, 1 μ m scan.

iDrive *(cont. from pg. 1)*

which can introduce undesirable cantilever bending, expose sample solutions to potentially harmful metal ions, and lose magnetic sensitivity due to corrosion in solution or oxidation over time. iDrive allows simplified auto-tunes in fluid, application of Q-control in fluid and non-destructive imaging of sensitive samples, particularly soft biological and polymer samples.

The iDrive accessory includes a cantilever holder and iDrive compatible probes. The holder can be operated in either iDrive AC mode or standard piezo-driven AC mode which is easily switchable in the software. It is compatible with MFP-3D accessories including the Closed Fluid Cell and BioHeater.

The new iDrive accessory will be available to customers by the end of Summer 2007. Visit our website for the latest announcements.



Lambda digest DNA imaged in fluid with the iDrive, 500nm scan.

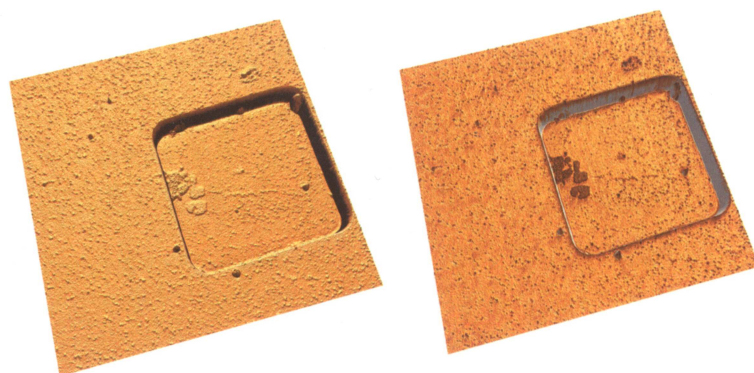


Figure 6: Contaminants on Si. Fundamental resonance mode phase data overlaid on topography (left) and second resonance mode amplitude data overlaid on the topography (right), 20 μ m scan.

Asylum Research Collaborates with the Institute of Microelectronics of Madrid on Advanced AFM Cantilever Dynamics

Asylum Research has announced its collaboration with Professor Ricardo Garcia's lab in the Institute of Microelectronics of Madrid (IMM) to further develop new techniques in the field of AFM cantilever dynamics, focusing on higher harmonic and multiple frequency measurement modes. The collaboration calls for Asylum Research to license intellectual property from the Spanish Council for Scientific Research (CSIC) and the joint development of advanced imaging techniques that allow new surface characterization of a variety of materials.

"Research coming out of the Garcia lab on cantilever dynamics is unsurpassed," said Dr. Roger Proksch, President and co-founder of Asylum Research. "His recent work dovetails perfectly into developments we have been pursuing with Dual AC Mode where we have seen extremely interesting results by employing higher cantilever resonant modes. Combining our efforts will lead to rapid advances in AFM surface characterization using this powerful new imaging mode."

Professor Ricardo Garcia, head of the Nanolithography and Scanning Probe lab of the Institute of Microelectronics of Madrid commented, "We strongly believe that multiple frequency imaging techniques will provide the next wave of AFM material characterization. It makes great sense for us to formally unite our efforts with Asylum because our conceptual developments can be readily implemented into their innovative MFP-3D AFM. We are confident that our joint efforts will benefit all AFM researchers and lead to the most rapid discoveries and dissemination of the technique."

For additional information on the CSIC, see their website at www.imm.cnm.csic.es/spm/index.html.